

OptiMOS[™]-T2 Power-Transistor





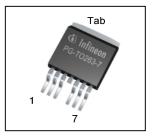
Features

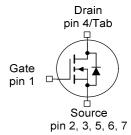
- N-channel Enhancement mode
- AEC Q101 qualified
- MSL1 up to 260°C peak reflow
- 175°C operating temperature
- Green Product (RoHS compliant)
- 100% Avalanche tested

Product Summary

V_{DS}	80	٧
R _{DS(on),max}	3.2	mΩ
I _D	160	Α

PG-TO263-7-3





Туре	Package	Marking
IPB160N08S4-03	PG-TO263-7-3	4N0803

Maximum ratings, at T_j =25 °C, unless otherwise specified

Parameter	Symbol	Conditions	Value	Unit
Continuous drain current ¹⁾	I _D	T _C =25°C, V _{GS} =10V	160	А
		$T_{\rm C}$ =100°C, $V_{\rm GS}$ =10 $V^{2)}$	120	
Pulsed drain current ²⁾	I _{D,pulse}	T _C =25°C	640	
Avalanche energy, single pulse ²⁾	E _{AS}	I _D =80A	350	mJ
Avalanche current, single pulse	I _{AS}	-	120	А
Gate source voltage	$V_{\rm GS}$	-	±20	V
Power dissipation	P_{tot}	T _C =25°C	208	W
Operating and storage temperature	$T_{\rm j},T_{\rm stg}$	-	-55 + 175	°C



Parameter	Symbol	Conditions	Values		Unit	
			min.	typ.	max.	
Thermal characteristics ²⁾						
Thermal resistance, junction - case	R_{thJC}	-	-	-	0.72	K/W
SMD version, device on PCB	R_{thJA}	minimal footprint	-	-	62	
		6 cm ² cooling area ³⁾	-	-	40	1

Electrical characteristics, at T_j =25 °C, unless otherwise specified

Static characteristics

Drain-source breakdown voltage	$V_{(BR)DSS}$	V_{GS} =0V, I_{D} = 1mA	80	ı	1	V
Gate threshold voltage	$V_{\rm GS(th)}$	$V_{\rm DS} = V_{\rm GS}, I_{\rm D} = 150 \mu {\rm A}$	2.0	3.0	4.0	
Zero gate voltage drain current	I _{DSS}	$V_{\rm DS} = 80 \text{V}, \ V_{\rm GS} = 0 \text{V}, \ T_{\rm j} = 25 ^{\circ} \text{C}$	1	0.03	1	μΑ
		$V_{\rm DS}$ =80V, $V_{\rm GS}$ =0V, $T_{\rm j}$ =125°C ²⁾	ı	10	200	
Gate-source leakage current	I _{GSS}	V_{GS} =20V, V_{DS} =0V	ı	ı	100	nA
Drain-source on-state resistance	$R_{DS(on)}$	V _{GS} =10V, I _D =100A	-	2.6	3.2	mΩ



Parameter	Symbol Conditions		Values			Unit
			min.	typ.	max.	
Dynamic characteristics ²⁾						
Input capacitance	Ciss		-	5961	7750	pF
Output capacitance	Coss	$V_{\rm GS}$ =0V, $V_{\rm DS}$ =25V, f=1MHz	-	2305	2997	1
Reverse transfer capacitance	C _{rss}		-	120	239	
Turn-on delay time	$t_{\sf d(on)}$		-	18	-	ns
Rise time	t _r	V _{DD} =40V, V _{GS} =10V,	-	11	-	
Turn-off delay time	$t_{d(off)}$	$I_{\rm D}$ =160A, $R_{\rm G}$ =3.5 Ω	-	30	-	
Fall time	t_{f}		-	38	-	
Gate Charge Characteristics ²⁾						
Gate to source charge	Q _{gs}		-	31	40	nC
Gate to drain charge	Q_{gd}	$V_{\rm DD}$ =64V, $I_{\rm D}$ =160A, $V_{\rm GS}$ =0 to 10V	-	19	37	
Gate charge total	Qg		-	86	112	
Gate plateau voltage	$V_{ m plateau}$		-	5.3	ı	V
Reverse Diode						
Diode continous forward current ²⁾	Is	T _25°C	-	-	160	А
Diode pulse current ²⁾	I _{S,pulse}	-T _C =25°C	-	-	640	
Diode forward voltage	V_{SD}	V _{GS} =0V, I _F =100A, T _j =25°C	-	0.9	1.3	V
Reverse recovery time ²⁾	t _{rr}	V_R =40V, I_F =50A, di_F/dt =100A/ μ s	-	74	-	ns
Reverse recovery charge ²⁾	Q _{rr}		-	160	-	nC

¹⁾ Current is limited by bondwire; with an $R_{\rm thJC}$ = 0.72K/W the chip is able to carry 186A at 25°C.

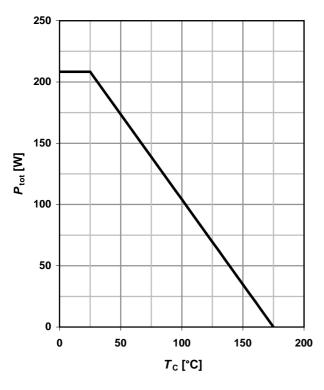
²⁾ Specified by design. Not subject to production test.

 $^{^{3)}}$ Device on 40 mm x 40 mm x 1.5 mm epoxy PCB FR4 with 6 cm 2 (one layer, 70 μ m thick) copper area for drain connection. PCB is vertical in still air.



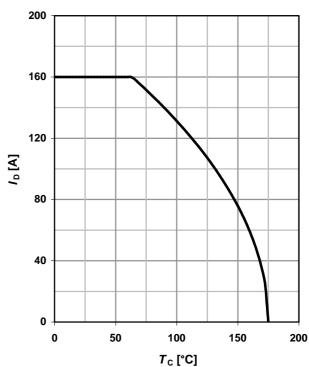
1 Power dissipation

$$P_{\text{tot}} = f(T_{\text{C}}); V_{\text{GS}} \ge 6 \text{ V}$$



2 Drain current

$$I_D = f(T_C)$$
; $V_{GS} = 10 \text{ V}$; SMD



3 Safe operating area

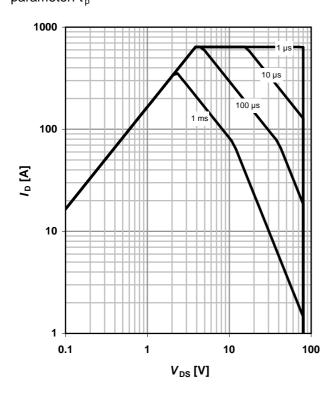
$$I_D = f(V_{DS}); T_C = 25 \text{ °C}; D = 0; SMD$$

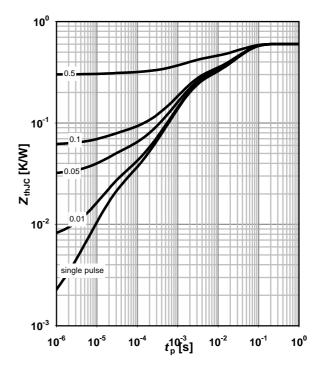
parameter: t_p

4 Max. transient thermal impedance

$$Z_{\rm thJC} = f(t_{\rm p})$$

parameter: $D=t_p/T$



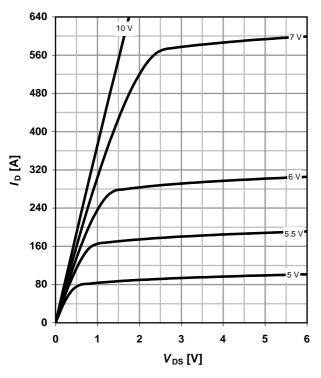




5 Typ. output characteristics

 $I_D = f(V_{DS}); T_j = 25 \text{ °C}; SMD$

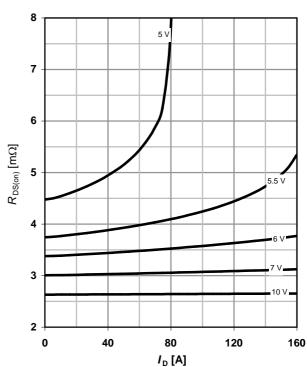
parameter: V_{GS}



6 Typ. drain-source on-state resistance

 $R_{DS(on)} = f(I_D); T_j = 25 \text{ °C}; SMD$

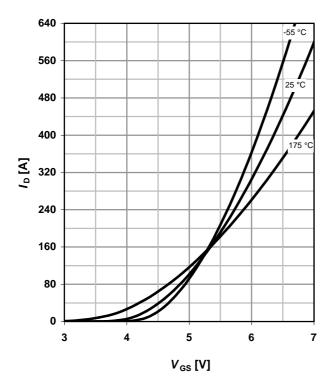
parameter: V_{GS}



7 Typ. transfer characteristics

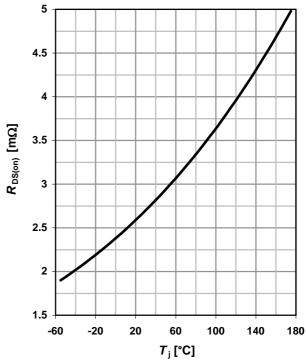
 $I_{\rm D} = f(V_{\rm GS}); V_{\rm DS} = 6V$

parameter: T_i



8 Typ. drain-source on-state resistance

$$R_{DS(on)} = f(T_j); I_D = 100 \text{ A}; V_{GS} = 10 \text{ V}; SMD$$





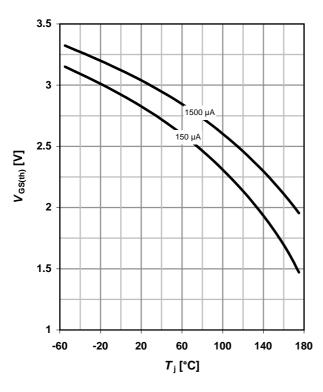
9 Typ. gate threshold voltage

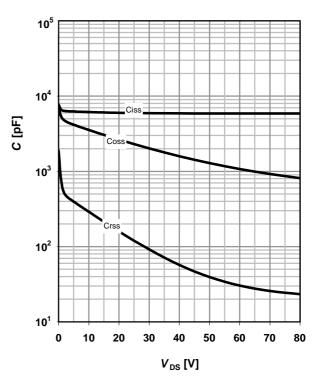
 $V_{GS(th)} = f(T_j); V_{GS} = V_{DS}$

parameter: I_D

10 Typ. capacitances

 $C = f(V_{DS}); V_{GS} = 0 V; f = 1 MHz$





11 Typical forward diode characteristicis

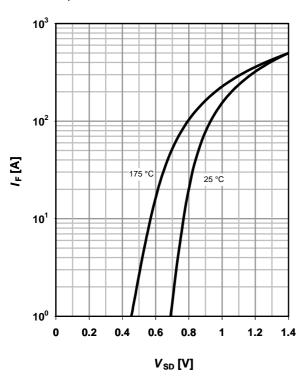
 $IF = f(V_{SD})$

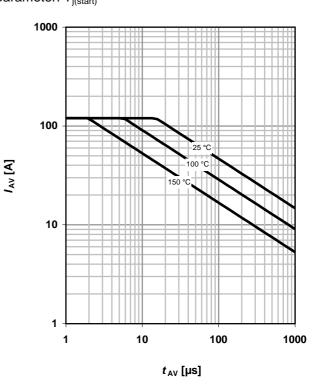
parameter: T_i

12 Avalanche characteristics

 $I_{AS} = f(t_{AV})$

parameter: T_{j(start)}



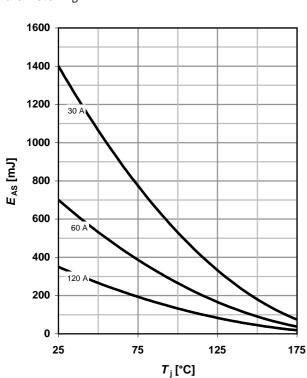




13 Avalanche energy

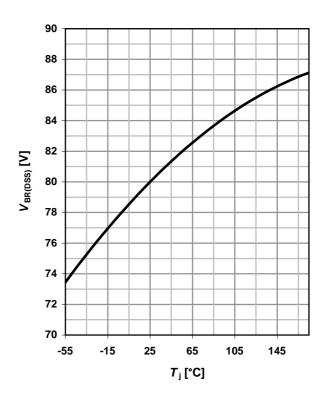
$E_{AS} = f(T_i)$

parameter: I_D



14 Drain-source breakdown voltage

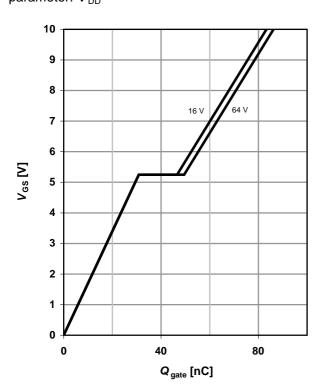
$$V_{BR(DSS)} = f(T_j); I_D = 1 \text{ mA}$$



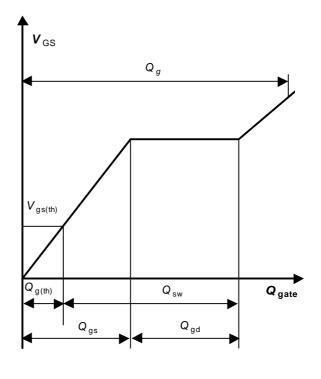
15 Typ. gate charge

 $V_{GS} = f(Q_{gate}); I_D = 160 \text{ A pulsed}$

parameter: V_{DD}



16 Gate charge waveforms





Published by Infineon Technologies AG 81726 Munich, Germany

© Infineon Technologies AG 2014 All Rights Reserved.

Legal Disclaimer

The information given in this document shall in no event be regarded as a guarantee of conditions or characteristics. With respect to any examples or hints given herein, any typical values stated herein and/or any information regarding the application of the device, Infineon Technologies hereby disclaims any and all warranties and liabilities of any kind, including without limitation, warranties of non-infringement of intellectual property rights of any third party.

Information

For further information on technology, delivery terms and conditions and prices, please contact the nearest Infineon Technologies Office (www.infineon.com).

Warnings

Due to technical requirements, components may contain dangerous substances. For information on the types in question, please contact the nearest Infineon Technologies Office. Infineon Technologies components may be used in life-support devices or systems only with the express written approval of Infineon Technologies, if a failure of such components can reasonably be expected to cause the failure of that life-support device or system or to affect the safety or effectiveness of that device or system. Life support devices or systems are intended to be implanted in the human body or to support and/or maintain and sustain and/or protect human life.

If they fail, it is reasonable to assume that the health of the user or other persons may be endangered.



Revision History

Version	Date	Changes		
Revision 1.0	20.06.2014	Final data sheet		